

NOTES:

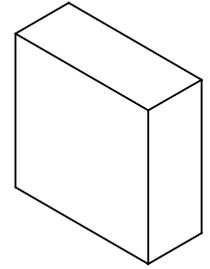
1. SUBSTRATE MATERIAL: Fused Silica

2. SURFACE S2 TO BE PARALLEL WITH S1 TO 30 arcsec

3. COATING (APPLY ACROSS CLEAR APERTURE)

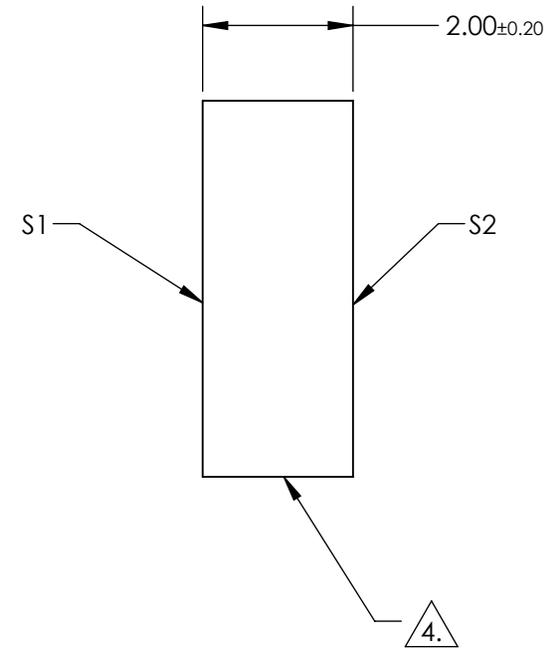
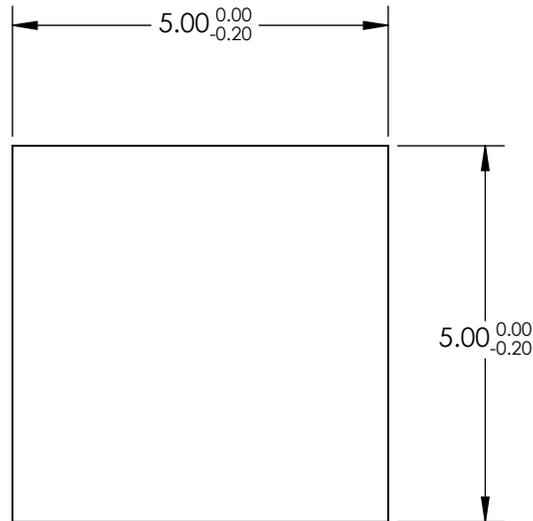
S1: R(avg)>99% @ 850-1150 nm, 0 deg AOI, Rs>99% @ 800-1150 nm, 45 deg AOI, Rp> 98.5 % @ ~850 – 1100 nm, 45 deg AOI

S2: NONE



4. FINE GRIND SURFACE

5. ROHS COMPLIANT



**FOR INFORMATION ONLY:  
DO NOT MANUFACTURE  
PARTS TO THIS DRAWING**

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE  
DIMENSIONS ARE FOR REFERENCE ONLY

**EO**® Edmund Optics®

	S1	S2
SURFACE QUALITY	20 - 10	COMMERCIAL POLISH
SURFACE FLATNESS	$\lambda/10$	N/A
BEVEL	PROTECTED AS NEEDED	PROTECTED AS NEEDED

THIRD ANGLE PROJECTION

ALL DIMS IN mm

TITLE	MIRROR 1/10 WAVE UF SILVER 800-1150NM 5mm SQ
DWG NO	22007
SHEET	7 OF 8